

024-23-04

Express Mail No. EV 809 346 864 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Laurent FILIPOZZI et al.

Confirmation No. 1944

Application No: 10/621,122

Group Art Unit: 3723

Filing Date: July 15, 2003

Examiner:

For: SURFACE PREPARATION FOR RECEIVING  
PROCESSING TREATMENTS

Atty. Docket No.: 4717-8100

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, applicants submit herewith one (1) reference for the Examiner's review and consideration. This reference was cited in the International Search Report and a copy is enclosed.

This reference is listed on the enclosed Form PTO-1449. It is respectfully requested that this references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee or certification is believed to be due for this submission since the references are being submitted prior to an initial office action for this application. Should any fees be required, however, please charge such fees to **Winston & Strawn LLP** Deposit Account No. 50-1814.

Date: 4/21/04

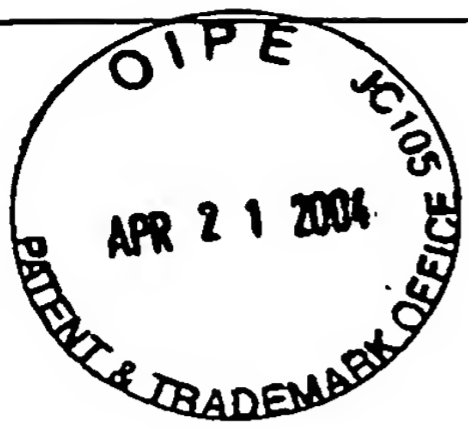
Respectfully submitted,

Allan A. Fanucci (Reg. No. 30,256)

**WINSTON & STRAWN LLP**  
**CUSTOMER NO. 28765**

Enclosures

(212) 294-3311

				ATTY. DOCKET NO.:		APPLICATION NO.:		
				4717-8100		10/621, 122		
				APPLICANT:				
				Laurent FILIPOZZI et al				
				FILING DATE:		GROUP:		
				July 15, 2003		3723		
<b>U.S. PATENT DOCUMENTS</b>								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA							
	AB							
	AC							
	AD							
	AE							
<b>FOREIGN PATENT DOCUMENTS</b>								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AF							
	AG							
	AH							
	AI							
<b>OTHER REFERENCES</b> <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
	AJ	Michael L. Free, XP-002266271, "Using Surfactants in iron-based CMP slurries to minimize residual particles", Surface Chemistries, Micromagazine (1998)						
	AK							
	AL							
<b>EXAMINER</b>				<b>DATE CONSIDERED</b>				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								